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(54) Title: APPARATUS FOR WAFER LEVEL TESTING OF SEMICONDUCTOR DEVICE

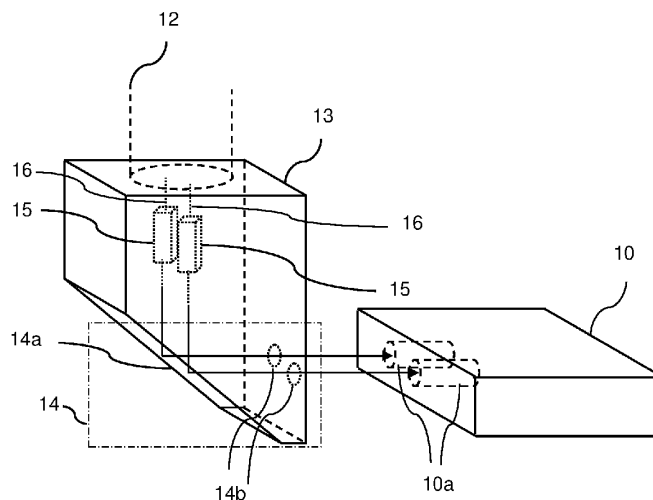


Figure 3

(57) Abstract: The present invention relates to an apparatus (1) for wafer level testing of a semiconductor device (10). The apparatus comprises an opto-electronic unit (11), an optical interface (13) and an optical fiber array (12) optically coupled between the opto-electronic unit (11) and the optical interface (13). The opto-electronic unit (11) transmits one or more optical test signals to the semiconductor device (10) and receives one or more optical response signals from the semiconductor device (10) for testing at least one function of the semiconductor device (10). The optical interface (13) optically couples the optical fiber array (12) and the semiconductor device (10). Furthermore, the optical interface (13) includes a steering element (14) for steering the optical test signals towards the semiconductor device (10) and the response signals towards the optical fiber array (12).

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